Supplementary Data

Synthesis of Mg and Zn Diolates and their Use in Metal Oxide Deposition

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SEM Images



Figure S1. SEM images of as-deposited layer **A** (top view, left) and a cross section image (right) using **7** as CVD precursor, deposited on Si/SiO₂ substrates.



Figure S2. SEM images of as-deposited layer **B** (top view, left) and a cross section image (right) using **7** as CVD precursor, deposited on Si/SiO₂ substrates.



Figure S3. SEM images of as-deposited layer **C** (top view, left) and a cross section image (right) using **7** as CVD precursor, deposited on Si/SiO₂ substrates.



Figure S4. SEM images of as-deposited layer **D** (top view, left) and a cross section image (right) using **7** as CVD precursor, deposited on Si/SiO₂ substrates.

EDX Spectra



Figure S5. EDX spectra of layer A by using an electron beam energy of 15 keV obtained from 7 by CVD.



Figure S6. EDX spectra of layer **B** by using an electron beam energy of 15 keV (left) and 3 keV (right) obtained from **7** by CVD showing the characteristic pattern of Zn, O, C and Si.



Figure S7. EDX spectra of layer **C** by using an electron beam energy of 15 keV (left) and 3 keV (right) obtained from **7** by CVD showing the characteristic pattern of Zn, O, C and Si.



Figure S8. EDX spectra of layer **D** by using an electron beam energy of 15 keV (left) and 3 keV (right) obtained from **7** by CVD showing the characteristic pattern of Zn, O, C and Si.



Figure S9. EDX spectrum of layer **E** by using an electron beam energy of 3 keV obtained from **5** by spin–coating showing the characteristic pattern of Mg, O, C and Si.



Figure S10. EDX spectrum of layer **F** by using an electron beam energy of 3 keV obtained from **7** by spin–coating showing the characteristic pattern of Zn, O, C and Si.

XPS Spectra

Survey Spectra of Layers A-F



Figure S11. *Ex situ* XPS spectra of the surface (left) and of the film (right) of layer **A** obtained from **7** by CVD.



Figure S12. *Ex situ* XPS spectra of the surface (left) and of the film (right) of layer **B** obtained from **7** by CVD.



Figure S13. Ex situ XPS spectrum of the surface of layer C obtained from 7 by CVD.



Figure S14. *Ex situ* XPS spectra of the surface (left) and of the film (right) of layer **D** obtained from **7** by CVD.



Figure S15. Ex situ XPS spectrum of the surface of layer E obtained from 5 by spin-coating.



Figure S16. Ex situ XPS spectrum of the surface of layer F obtained from 7 by spin-coating.



Detailed spectra of layers A, B, D - F

Figure S17. *Ex situ* detailed XPS spectra of the Zn $2p_{3/2}$ peak (left), O 1s peak (middle) and C 1s peak (right) of layer **A** obtained from **7** by CVD.



Figure S18. *Ex situ* detailed XPS spectra of the Zn $2p_{3/2}$ peak (left), O 1s peak (middle) and C 1s peak (right) of layer **B** obtained from **7** by CVD.



Figure S19. *Ex situ* detailed XPS spectra of the Zn $2p_{3/2}$ peak (left), O 1s peak (middle) and C 1s peak (right) of layer **D** obtained from **7** by CVD.



Figure S20. Ex situ detailed XPS spectra of the Mg 2p peak (left) and O 1s peak (right) of layer E



obtained from **5** by spin–coating.

Figure S21. *Ex situ* detailed XPS spectra of the Zn $2p_{3/2}$ peak (left), O 1s peak (middle) and C 1s peak (right) of layer **F** obtained from **7** by spin–coating.

GIXRD Spectra



Figure S22. GIXRD spectra of layer A with reflections of ZnO (red), applied deposition parameters are given in Table 3.



Figure S23. GIXRD spectra of layer **B** with reflections of ZnO (red), applied deposition parameters are given in Table 3.



Figure S24. GIXRD spectra of layer **C** with reflections of ZnO (red), applied deposition parameters are given in Table 3.

Layer _	Surface composition [mol%]				
	Zn	Mg	0	С	F
А	12.2		29.8	58.0	
В	30.0		34.1	37.9	
С	28.4		36.0	35.6	
D	32.5		35.0	32.5	
Е		30.9	45.2	17.6	6.3
F	30.5		51.1	18.4	

Table S1. Elemental composition of the surface of layers $\mathbf{A} - \mathbf{F}$.

NMR Spectra

125

115

105



95 90 85 80 75 70 65 60 55 50 45 40 35 30 25 20 15 10 5 0

Chemical shift [ppm]



¹³C NMR spectrum of **5** in CDCl₃.





HMQC NMR spectrum of 5 in CDCl₃.



HMBC NMR spectrum of **5** in CDCl₃.





Chemical shift [ppm]

HMQC NMR spectrum of 7 in C₆D₆.



HMBC NMR spectrum of 7 in C₆D₆.



IR Spectra

IR spectrum of 3 (CHCl₃, NaCl).







